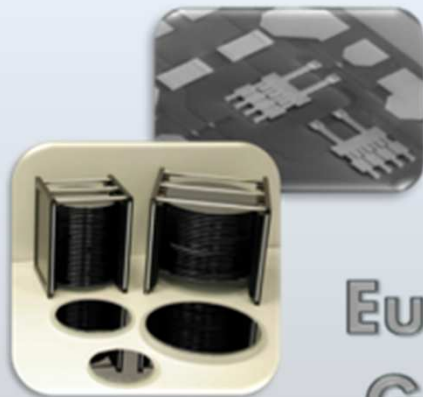




**OMMIC**

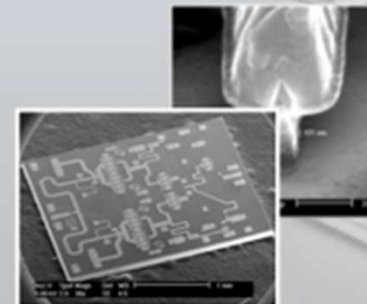
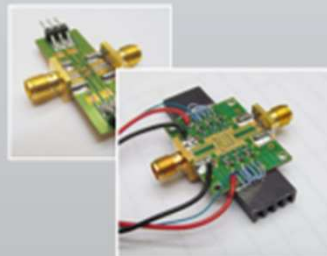
*Innovating with III-V's*



# OMMIC



Europe's Independent  
GaAs InP GaN MMIC  
Supplier





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## Mixed D/A ED02AH process for radar control functions and new GaN/Si for hyper-frequency power applications





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# Europe's Independent III-V Full-Service Foundry

3





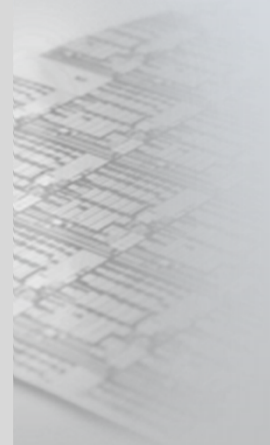
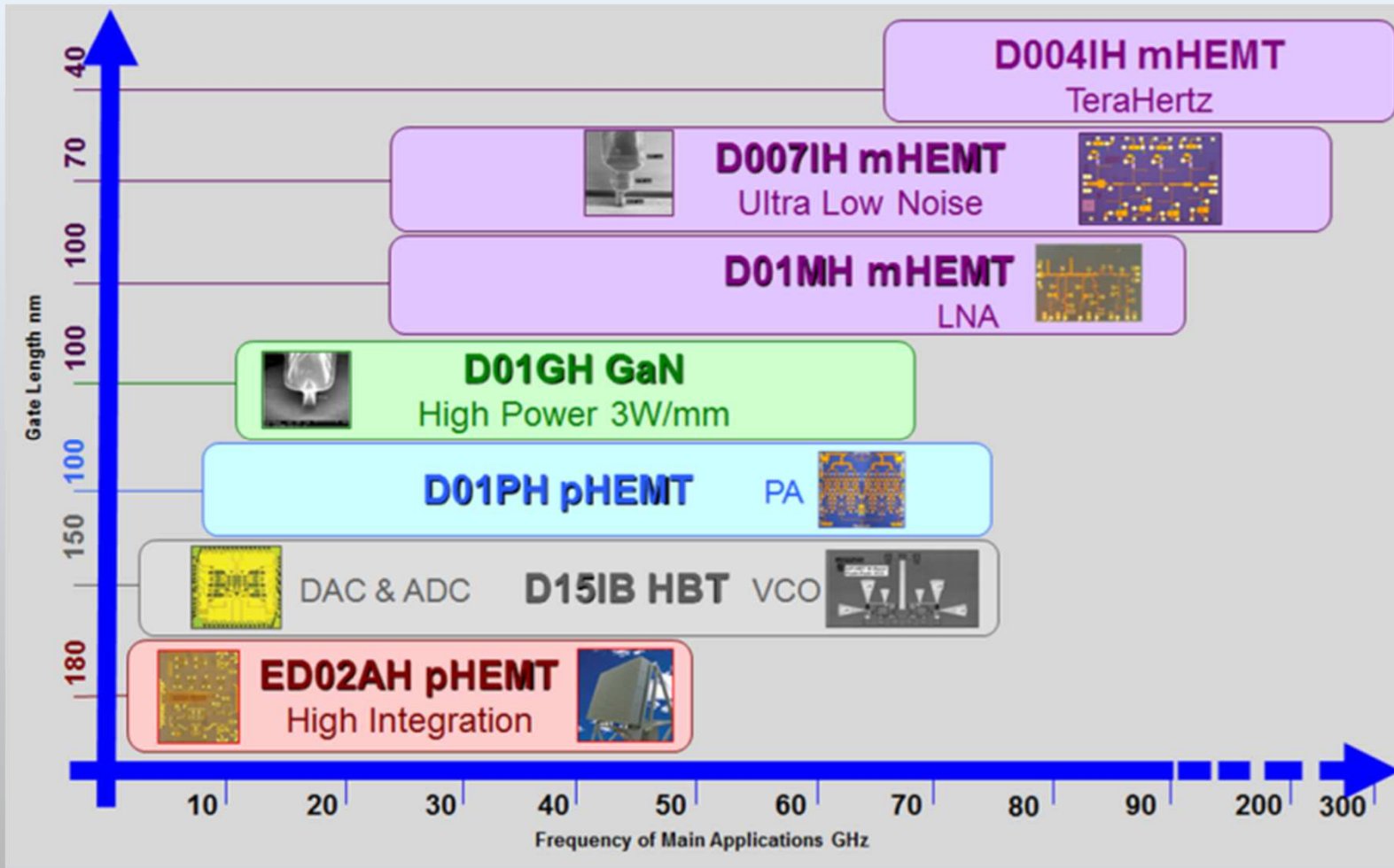
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# OMMIC PROCESS

4





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5

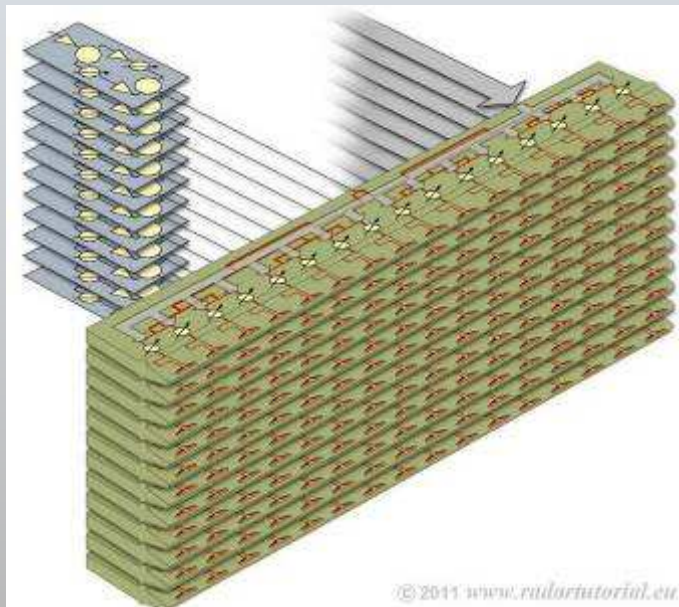
# OMMIC ED02AH D/A mixed process for control functions





# Introduction

- III/V provide optimum trade-offs in terms **NF, gain, power and linearity** for various applications including wireless telecommunication infrastructure, security scanners, radars and instrumentation.
- A weaker feature of III/V technologies → limited level of integration.



We will show how E/D PHEMT processes enable the integration of analogue functions like **phase shifters and attenuators with serial to parallel converters**

E/D → **Serial ctrl** → **High integration** → **cost reduction**

All integrated on the same chip to achieve state of the art performance through the example of **Corechips**.



# Electronically steerable antenna example

The orientation of the beam is obtained by the use of variable phase shifters attached to each radiating element

The diagram on the left illustrates the principle of beam steering. It shows a linear array of five radiating elements, each connected to a phase shifter labeled  $\varphi_4, \varphi_3, \varphi_2, \varphi_1, \varphi_0$  from left to right. The distance between adjacent elements is denoted as  $d$ . A red arrow indicates the direction of the main beam, and the angle it makes with the normal to the array is labeled  $\Phi$ . The equation below the diagram is:

$$\varphi_i = \varphi_0 + 2.i.\pi.d / \lambda . \sin(\Phi)$$

The photograph on the right shows a large, octagonal antenna structure covered in a dense grid of radiating elements, mounted on a concrete base. The source of the image is cited as U.S. Air Force/SSGT Lono Kollars.

The side lobes may then be controlled by variable attenuators attached to each element

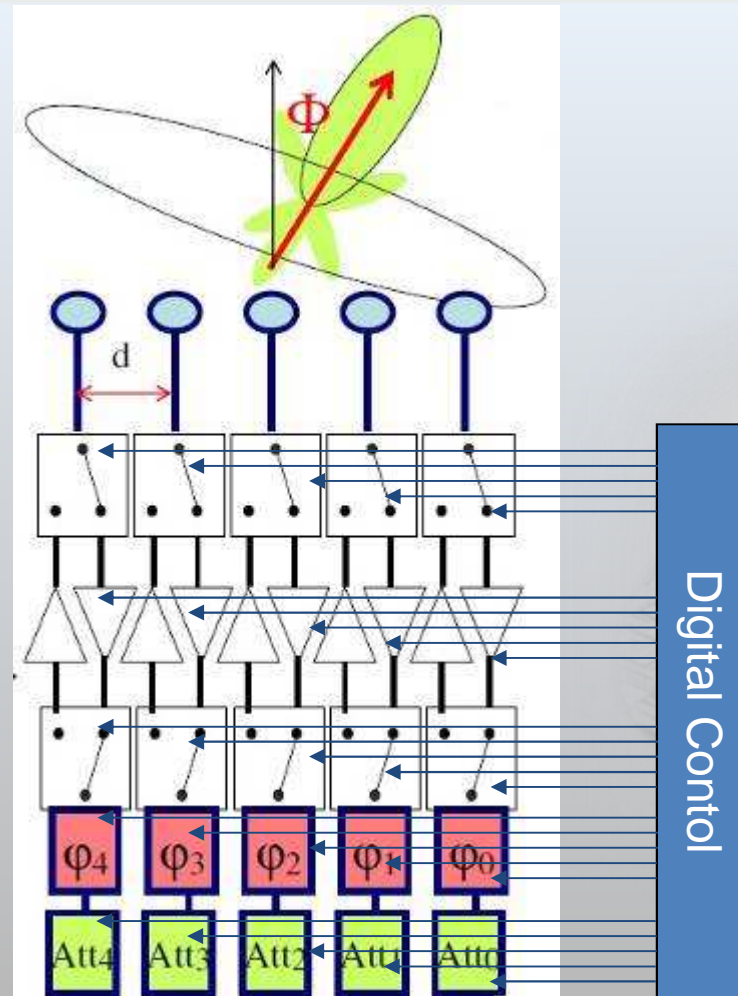


## Electronically steerable antenna example

Each antenna element may contain :

- A variable phase shifter
- A variable attenuator
- Switches, to be able to use the same system in receive or transmit modes
- Amplifiers:

*to compensate the losses and create some gain,  
to reduce the noise in receive mode,  
to create enough power to drive power amplifiers in transmit mode*



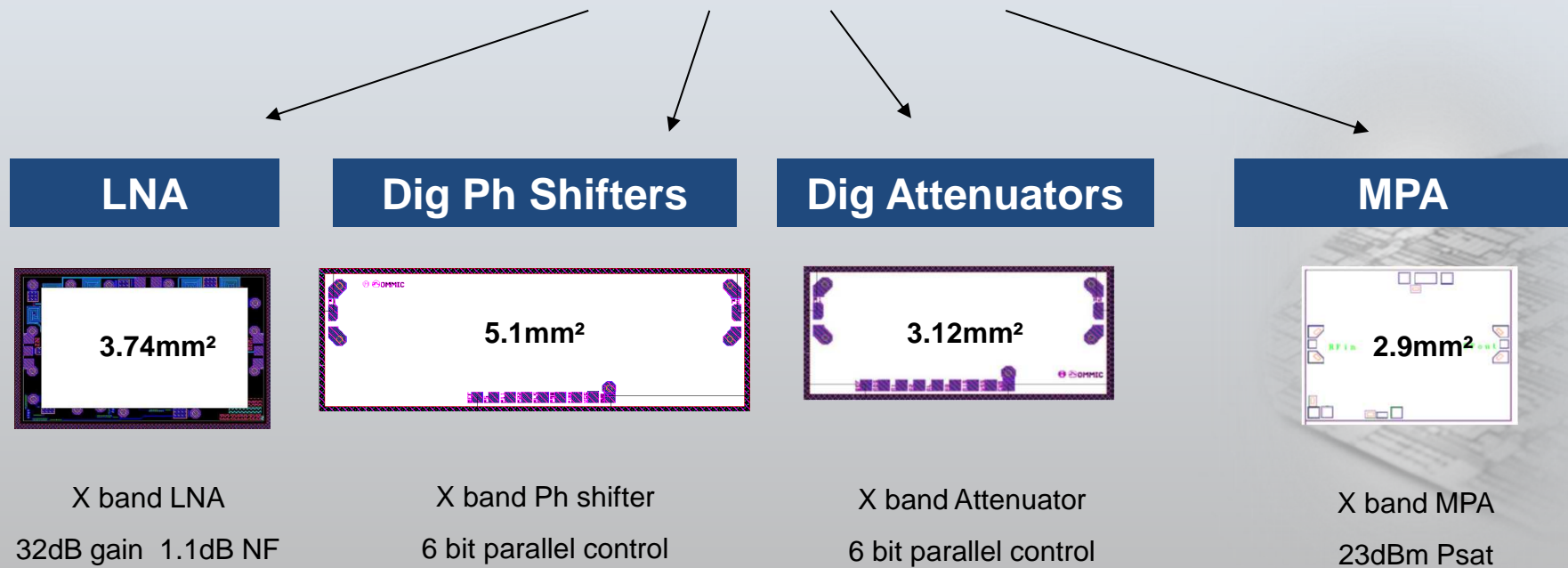




# From single function to multiple function chip

Due to higher frequency of radar application , integration of functions become a key aspect of designs. *Below is the X band example*

## Single functions already exists





# Serial Interface need : 6 bit corechip example

With 12 bits (or more) for a full core chip, we are faced with a connection problem:



Up to 24 pads (2 per bit if +/- control is required) to drive the 12 bits



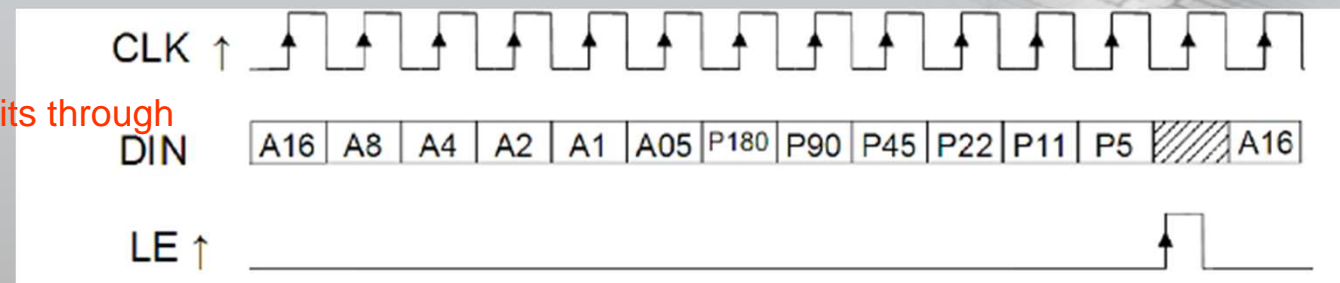
24 bonding wires per circuit, multiplied by hundreds of circuits



The solution is to place the SIPO on the chip



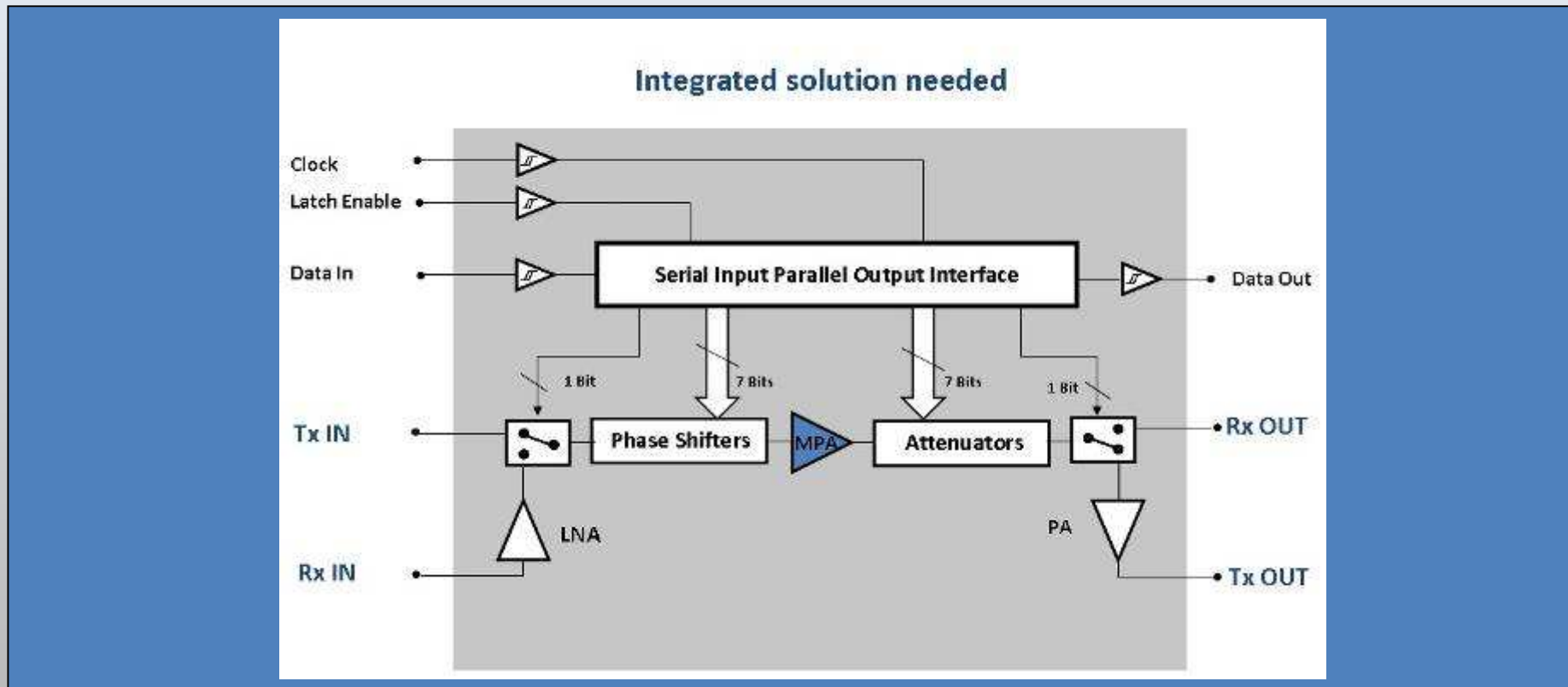
Only one PIN to control all bits through  
Serial Input Parallel Output





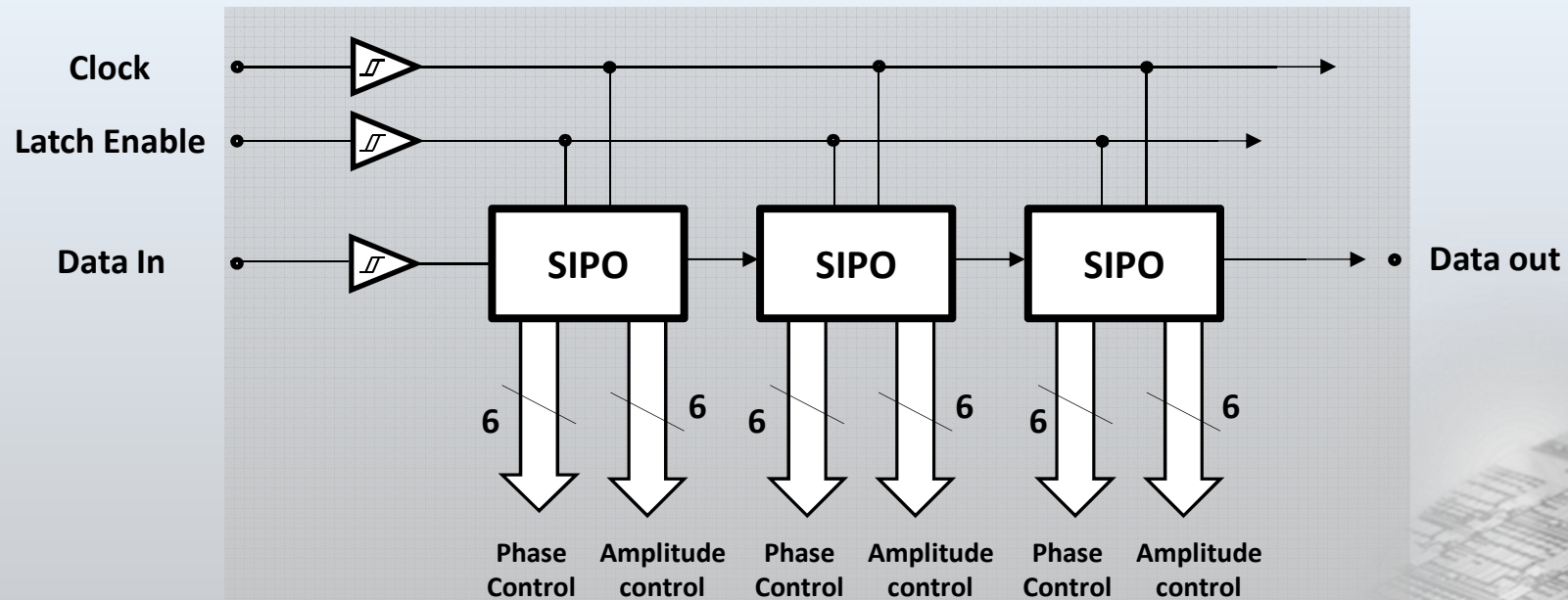
# From single function to multiple function chip

Due to higher frequency of radar application , integration of functions become a key aspect of designs. *Below is the X band example*





# Multiple Cascaded devices : The SIPO Advantage



**N devices to control :**

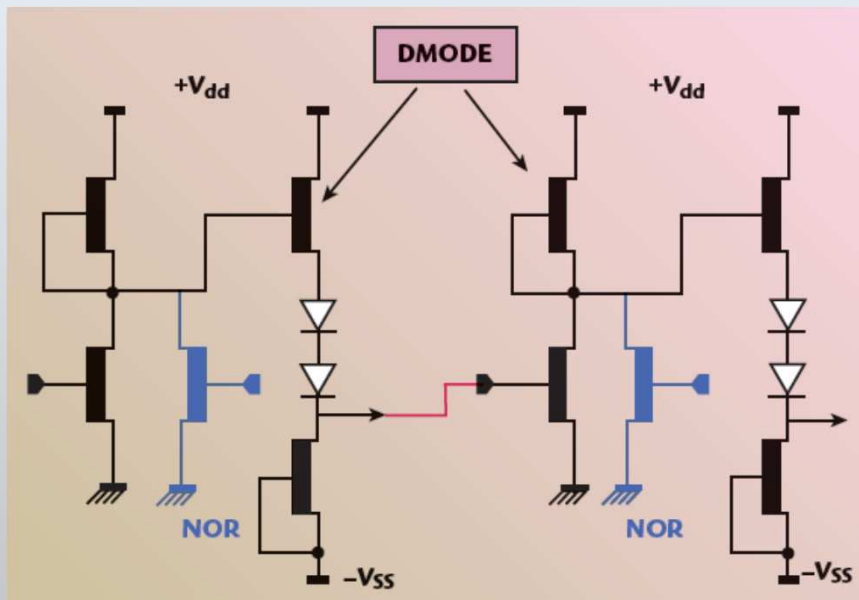
**2 x 6 x N wires for Parallel controled devices**

**Only 3 wires for cascaded SIPO enabled devices**

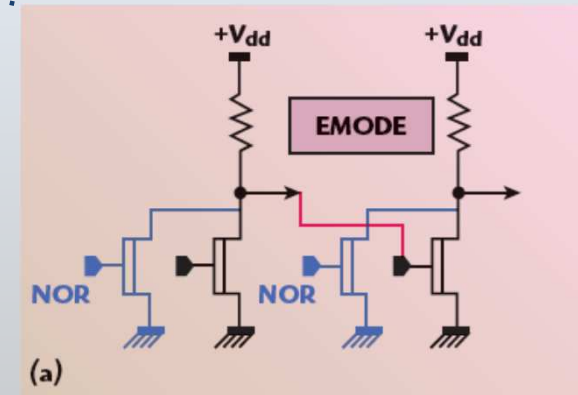


# How to realize the SIPO

Efficient SIPO on chip requires Enhancement mode process



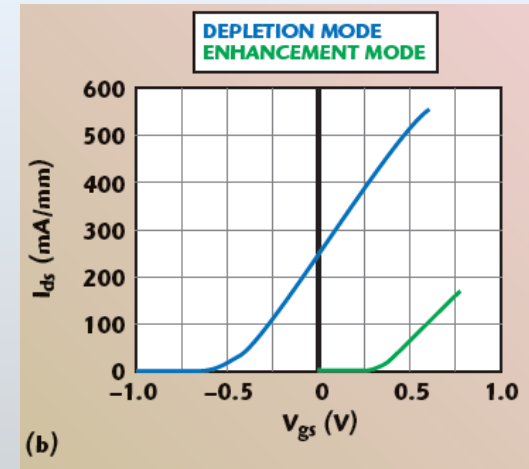
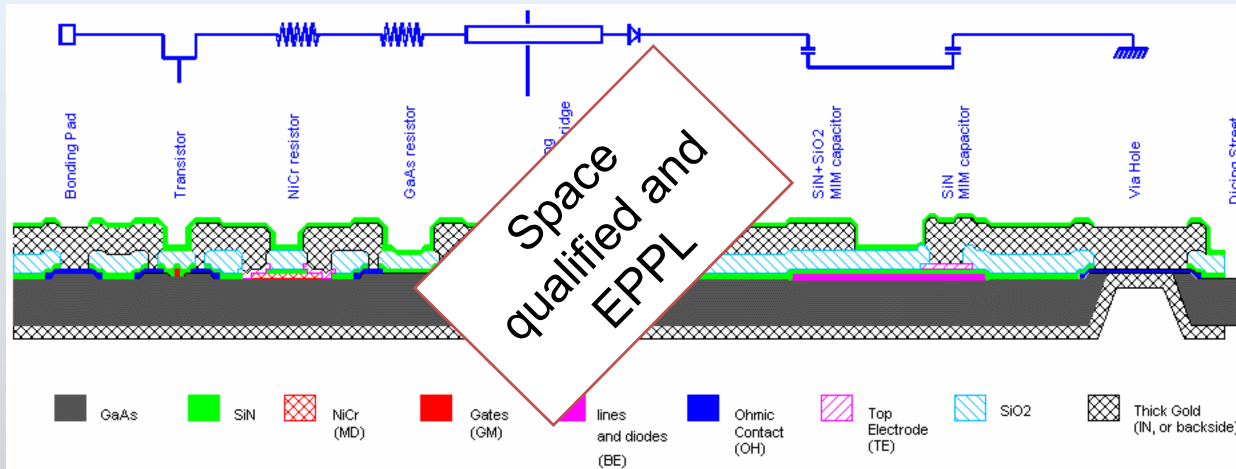
With D-mode transistors  
Requires negative supply + DC  
level shifting



With E-mode transistors  
Direct coupling



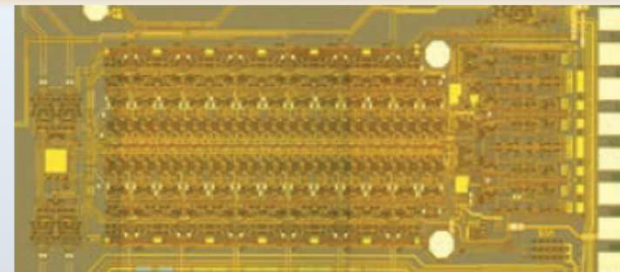
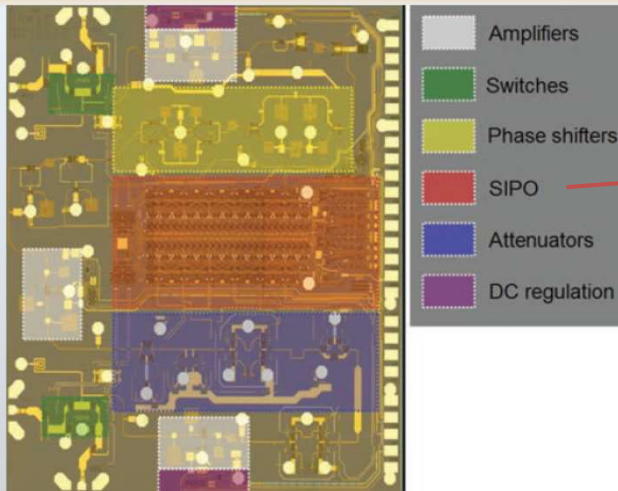
## OMMIC E/D process : ED02AH



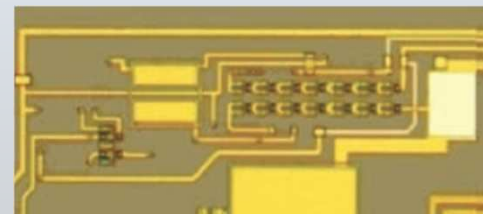
- Hetero-epitaxy with a pseudomorphic (GaInAs) active layer
- 0.18μm gate length (60 GHz Ft)
- Depletion and Enhancement mode recessed transistors: V<sub>t</sub>=0.225V or -0.9V
- 2 types of diodes (0.18μm "GM" and 3μm "BE") for mixing, level shifting, or varactors.
- 3 types of Resistors : 40, 200 or 500 Ohms.square
- 2 types of MIM Capacitors : 50 or 400 pF/mm<sup>2</sup>
- Full SiN + SiO<sub>2</sub> + SiN protection ensuring high reliability
- SiO<sub>2</sub>/SiN + air bridge isolation between layers to reduce the parasitic capacitances.
- 1.25μm or 2.5μm thick gold metallisation for interconnections and spiral inductors.
- Via holes through the 100μm substrate to reduce parasitic inductances to ground.



# Examples of SIPOs



26 bits SIPO

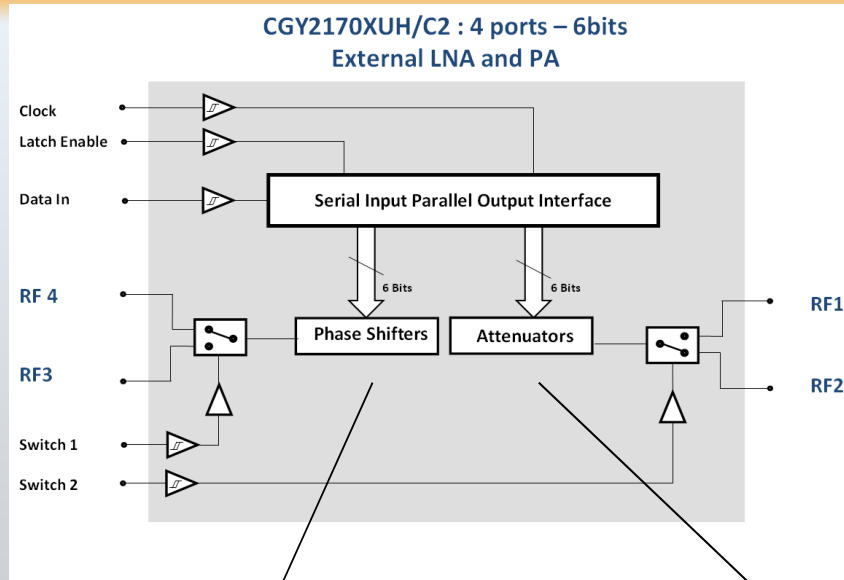


Number of control bits	Number of transistor gates	Global DC consumption including drivers and latches
12	700 (58 / bit)	150 mW (13 mW / bit)
26	1500 (58 / bit)	350 mW (13 mW / bit)
18	1500 (83 / bit)	300 mW (17 mW / bit)
24	1500 (63 / bit)	200 mW (8 mW / bit)
26	1200 (46 / bit)	60 mW (2.3 mW / bit)
10	800 (80 / bit)	4 mW (0.3 mW / bit) <small>Low speed</small>

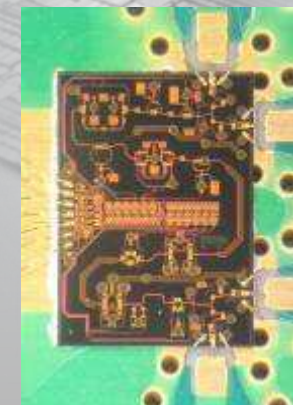
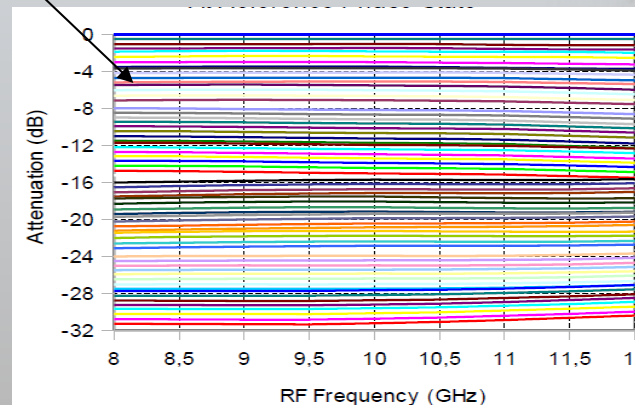
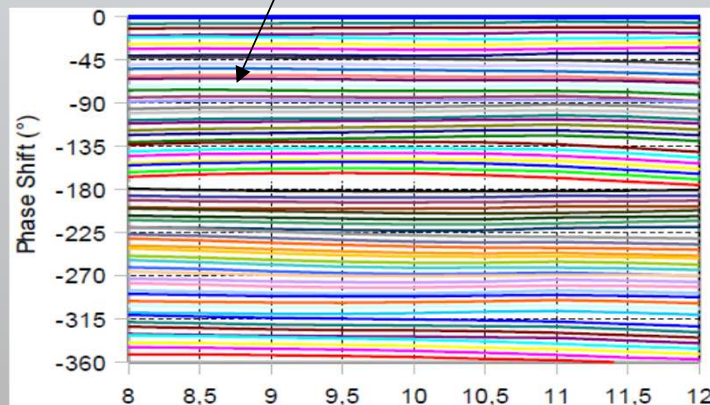




# Examples of X band Corechips



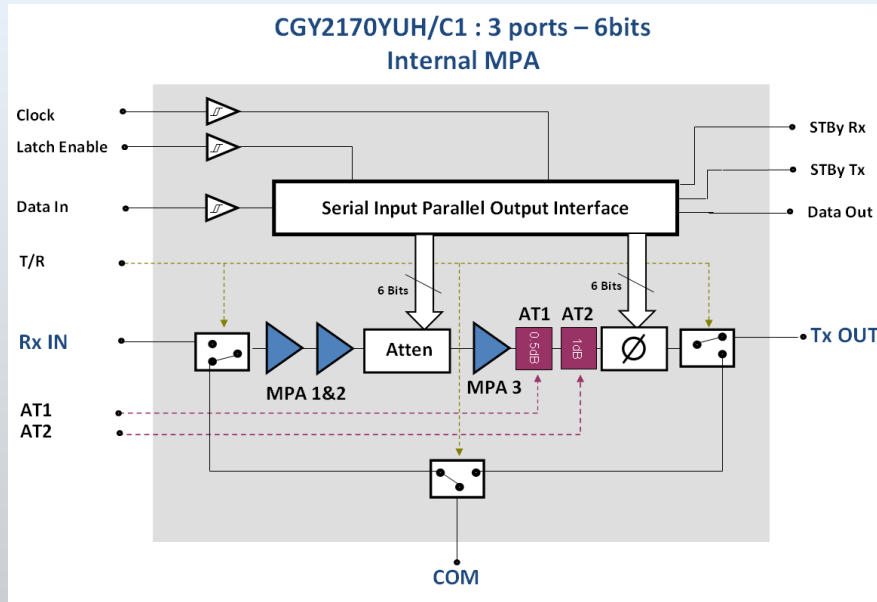
- ▶ Operating Range : 8 GHz to 12 GHz
- ▶ Insertion Loss : 15 dB @ 10 GHz
- ▶ RMS Phase Error  $\approx 3.0^\circ$  @ 10 GHz
- ▶ RMS Amplitude Error  $\approx 0.3$  dB @ 10 GHz
- ▶ Input P1dB  $\approx +20$  dBm
- ▶  $S_{11}$  &  $S_{22} \approx -15$  dB @ 10 GHz (all states)
- ▶ Total Power Consumption  $\approx 40$  mW
- ▶ Chip size = 4000 x 2850  $\mu\text{m}$
- ▶ Tested, Inspected Known Good Die (KGD)
- ▶ Samples Available





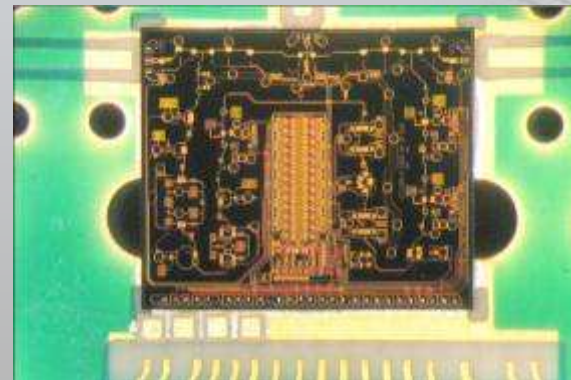


# Examples of X band Corechips



- ▶ Operating Range : 8 GHz to 12 GHz
- ▶ Gain Tx/Rx : 6 dB @ 10 GHz
- ▶ RMS Phase Error  $\approx 3.0^\circ$  at 9-10 GHz
- ▶ RMS Amplitude Error  $\approx 0.4$  dB from 8-11 GHz
- ▶ Output P1dB Tx  $\approx +11$  dBm
- ▶ Output P1dB Rx  $\approx +11$  dBm
- ▶  $S_{11}$  &  $S_{22} < -17$  dB @ 10 GHz (all states)
- ▶ Total Power Consumption  $\approx 0,36$  W
- ▶ Chip size = 4700 x 3800  $\mu$ m
- ▶ Tested, Inspected Known Good Die (KGD)
- ▶ Samples Available

Separated register for Rx and Tx  
External additional attenuators

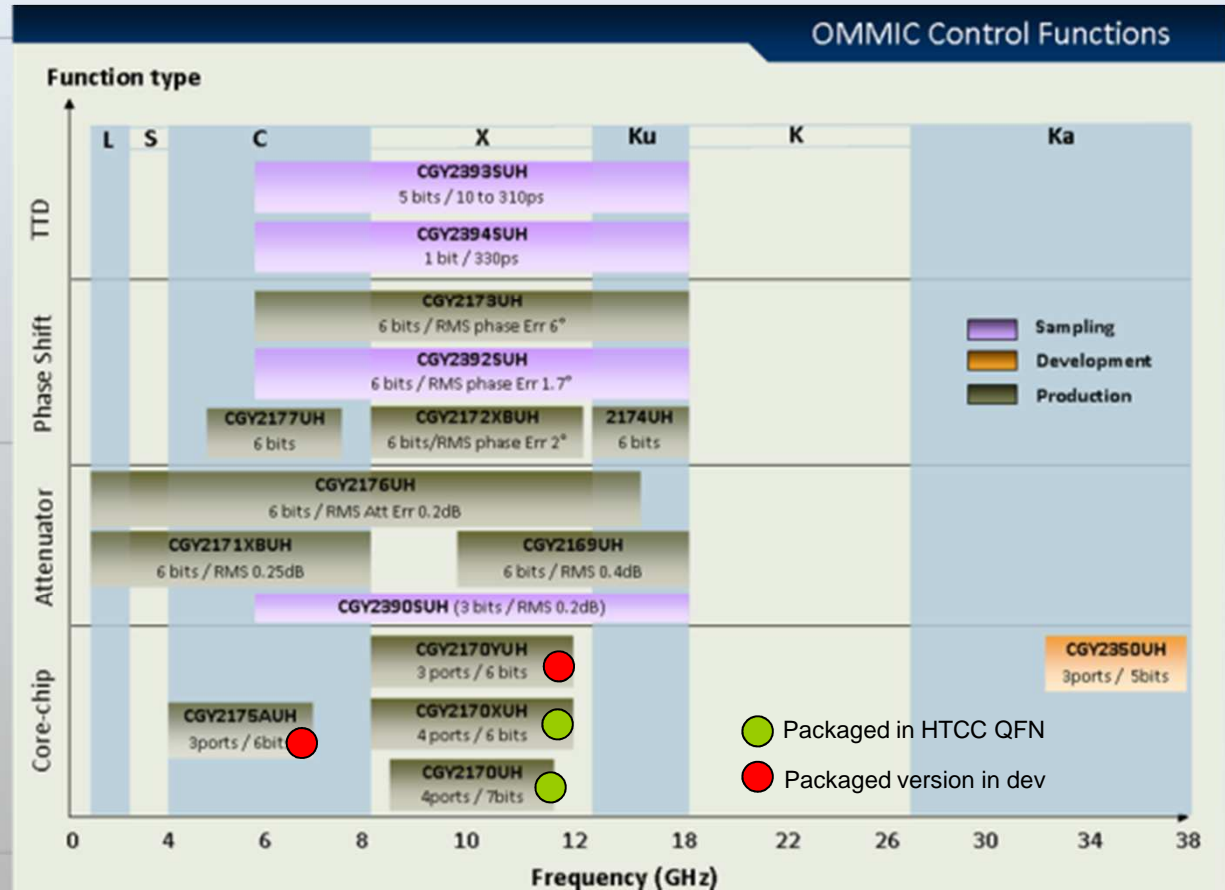
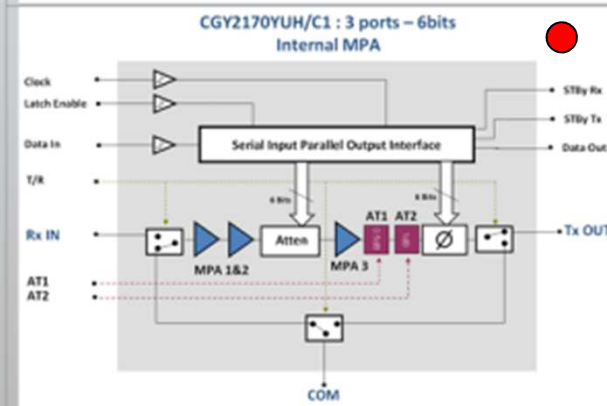
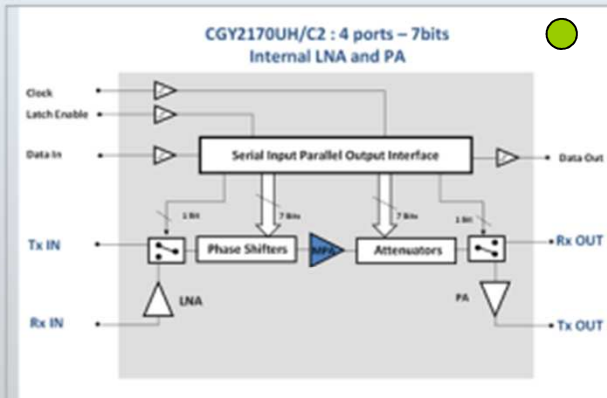






## OMMIC Corechip offer

- More than 15 Core chip in production from C band to Ka Band
- More than 40 Custom Corchip designed for customers



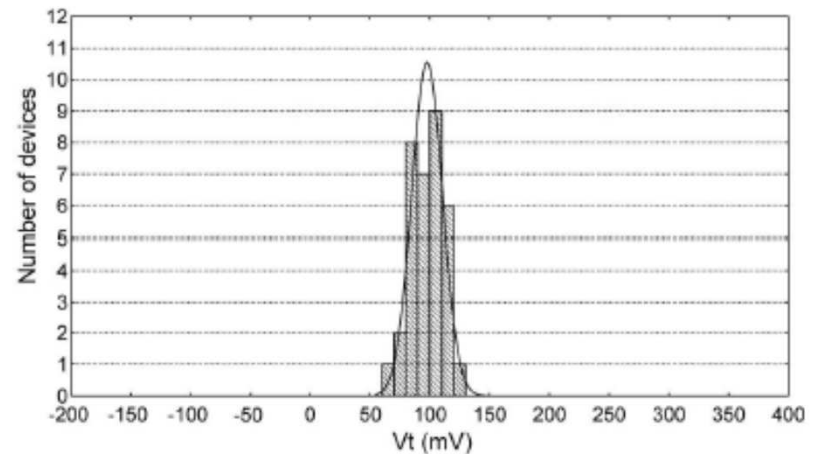


## future control function

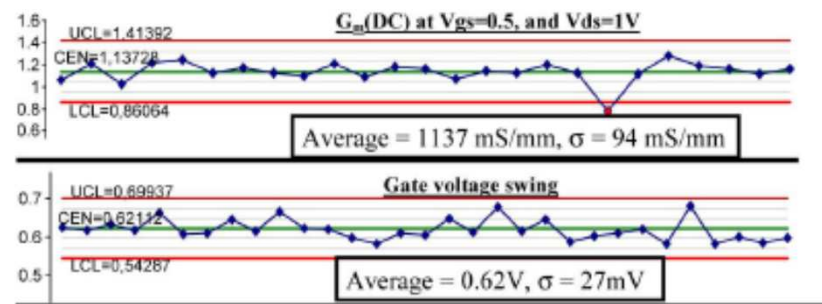
For the Development of Core Chips including SIPO above 60 GHz, a new process is required.

OMMIC has thus developed a true E-mode 0.1um process using a metamorphic layer

- ⊕ 200 GHz Ft, 300 GHz Fmax  
     ▶ => E band Core Chip possible
- ⊕ 15 dB MSG @ 30 GHz
- ⊕ E-mode => easy SIPO
- ⊕ Large Vg swing => switches
- ⊕ Same passives than ED02AH



(a)



IEEE TRANSACTIONS ON ELECTRON DEVICES, VOL. 54, NO. 7, JULY 2007, Hassan Maher (OMMIC) and AI



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# OMMIC GaN / Si



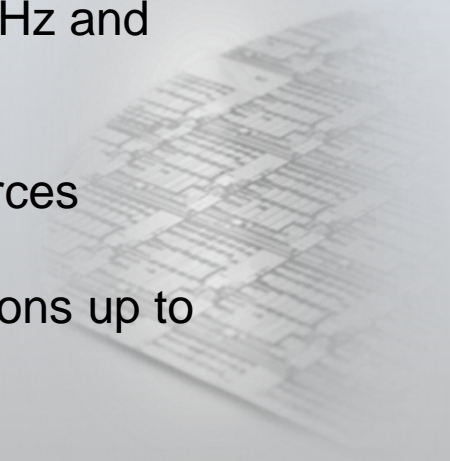


# mmW GaN HEMT on Si : Goal

22

**The choice of a GaN heterostructure on Si is dictated by the following points:**

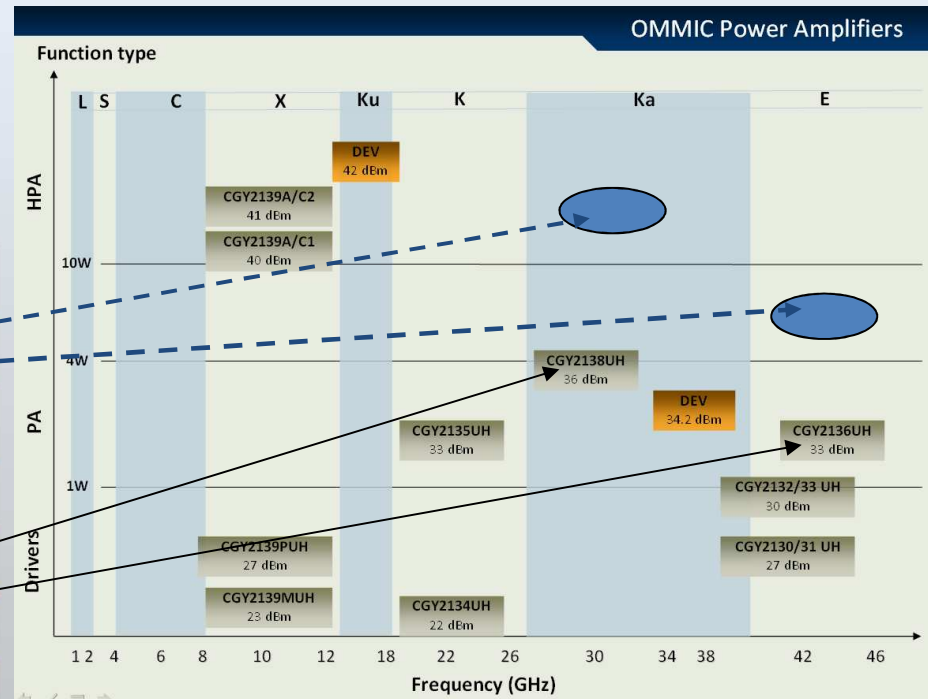
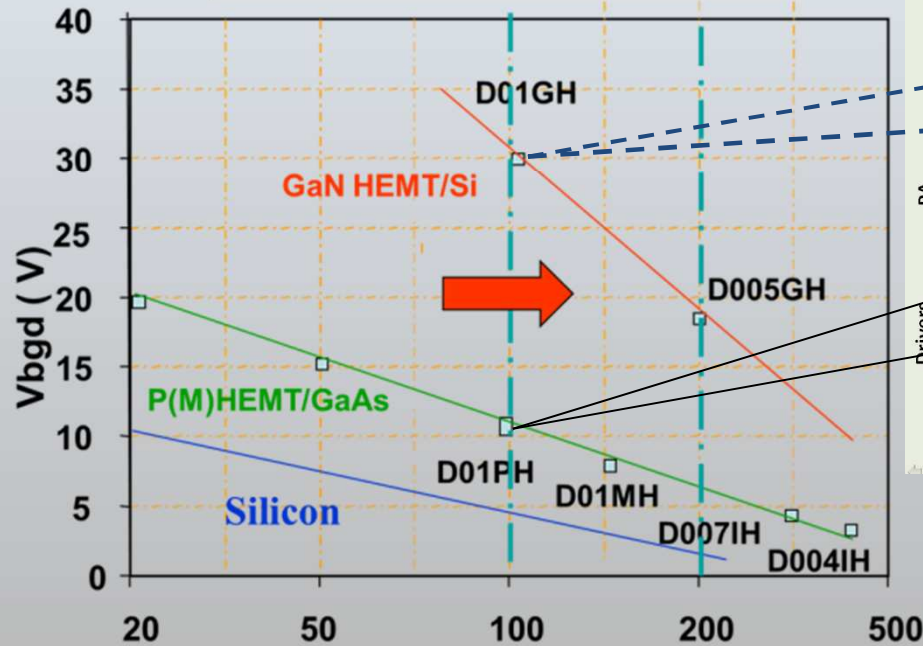
- Increase power density 3 times the current GaAs technology
- Address applications up to 20W, compatible with the Si Thermal conductance, primarily targeting frequency bands from 15 GHz and 100 GHz .
- Access to the epitaxial material without depending on SiC sources
- Full replacement of GaAs processes for professional applications up to 100GHz at a lower cost/mm<sup>2</sup>





## mmW GaN HEMT on Si

- ▶  $I_{dss} (0V) = 650 \text{ mA/mm}$
- ▶  $V_t = -1.5V$
- ▶  $G_m \text{ max ext} = 600 \text{ mS/mm}$
- ▶  $F_t = 100 \text{ GHz}$ ,  $F_{max} = 180 \text{ GHz}$  @  $V_{ds} = 3V$
- ▶  $MSG = 14 \text{ dB}$  @  $30 \text{ GHz}$
- ▶  $V_{bgd} \text{ min} = 30V$ , typical =  $40V$  ( $V_{ds} \text{ max} = 24V$ )
- ▶  $V_{dd} = 15V$
- ▶  $P_{sat} > 2.5 \text{ W/mm}$  at  $30 \text{ GHz}$  ( $V_{ds} = 15V$ )



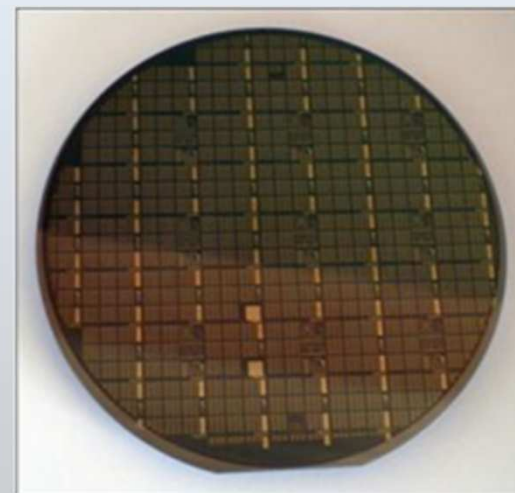


# Advanced release of GaN/Si process

*Preliminary Design Kit available under ADS or AWR*

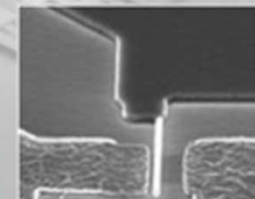
## D01GH :

- ▶  $I_{dss} (0V) = 650 \text{ mA/mm}$
- ▶  $V_t = -1.5V$
- ▶  $G_m \text{ max ext} = 600 \text{ mS/mm}$
- ▶  $F_t = 100 \text{ GHz}, F_{max} = 180 \text{ GHz} @ V_{ds} = 3 \text{ V}$
- ▶  $MSG = 14 \text{ dB} @ 30 \text{ GHz}$
- ▶  $V_{bgd \text{ min}} = 30V, \text{ typical} = 40V (V_{ds \text{ max}} = 24V)$
- ▶  $V_{dd} = 15V$
- ▶  $P_{sat} > 2.5 \text{ W/mm at } 30 \text{ GHz} (V_{ds} = 15V)$



## Applications :

- High frequency Power Amplifiers *10GHz to 94 GHz*
- Robust Low Noise Amplifiers (*< 20 GHz*)
- Robust Control Functions
- High Linearity Mixers



**0.11  $\mu\text{m}$  gate (GaN on Si)**

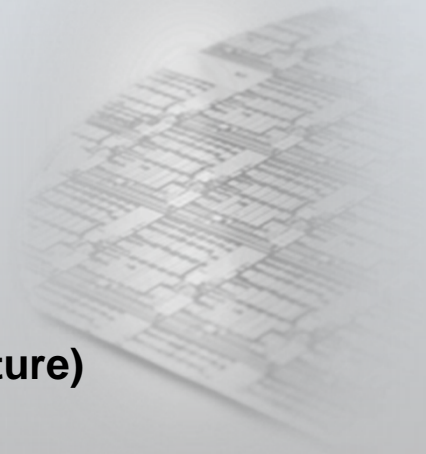




# D01GH Key power applications and targets

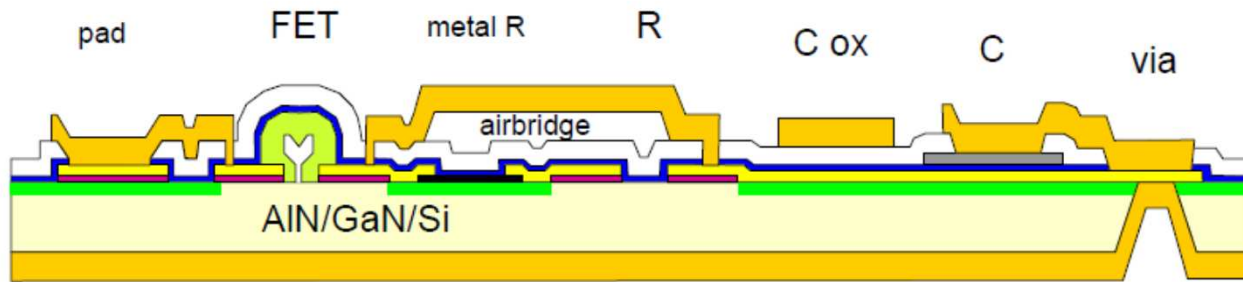
25

- **Scaled GaN /Si ( 30% shorter gate) can replace GaAs and InP for power applications with following power capability :**
  - 1 W @ 94GHz
  - 6 W @ 45GHz
  - 12 W @ 30GHz
  - 25 W @ 10GHz
- **3 KEY features are required :**
  - In situ SiN passivation ( reduced lag effects in planar structure)
  - Si substrate with proprietary buffer and extension to 6 inch
  - Regrown ohmics ( for high gm and low noise)

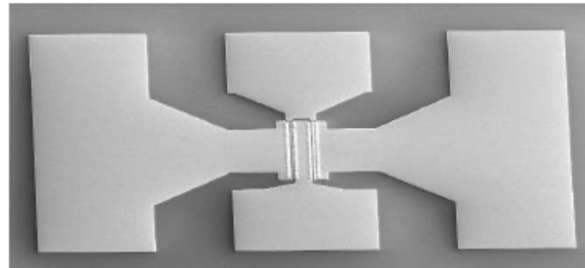




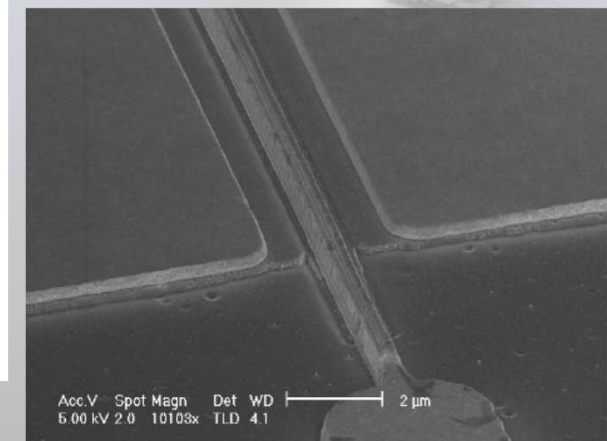
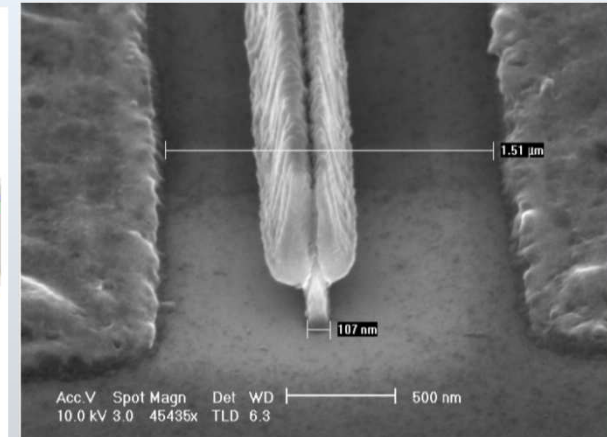
# D01GH PROCESS FLOW



- European epi ( EPIGaN)
- Regrown ohmics ( for high gm)
- Mushroom gate ( 100nm, 60nm)
- In situ SiN passivation ( for low lag effects <10%)



2x70um HEMT





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**Thank you for your attention**



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